

Description

The AP80P04D uses advanced trench technology to provide excellent $R_{DS(ON)}$, low gate charge and operation with gate voltages as low as 4.5V. This device is suitable for use as a Battery protection or in other Switching application.

General Features

 $V_{DS} = -40V I_{D} = -80 A$

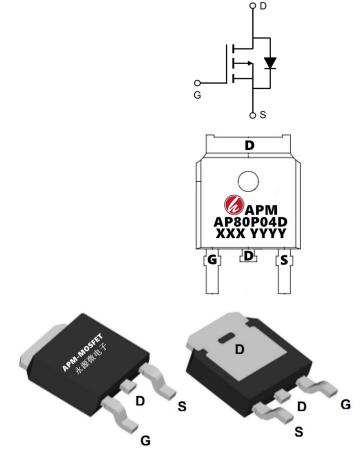
 $R_{DS(ON)} < -10m\Omega$ @ $V_{GS}=-10V$ (Type: 7.0m Ω)

Application

Battery protection

Load switch

Uninterruptible power supply



Package Marking and Ordering Information

Product ID	Pack	Marking	Qty(PCS)
AP80P04D	TO-252-3L	AP80P04D XXX YYYY	2500

Absolute Maximum Ratings (TC=25°Cunless otherwise noted)

Symbol	Parameter	Rating	Units	
Vos	Drain-Source Voltage	-40	V	
Vgs	Gate-Source Voltage	±20	V	
I _D @T _C =25°C	Continuous Drain Current, V _{GS} @ -10V ¹	-80	А	
I _D @T _C =100°C	Continuous Drain Current, V _{GS} @ -10V ¹	-56	Α	
Ідм	Pulsed Drain Current ²	-280	Α	
EAS	Single Pulse Avalanche Energy ³	y ³ 500		
las	Avalanche Current	-50	Α	
P _D @T _C =25°C	Total Power Dissipation ⁴	52.1	W	
Тѕтс	Storage Temperature Range	-55 to 150	°C	
TJ	Operating Junction Temperature Range	-55 to 150	°C	
$R_{ heta}$ JA	Thermal Resistance Junction-Ambient ¹	62	°C/W	
Rejc	Thermal Resistance Junction-Case ¹	2.4	°C/W	



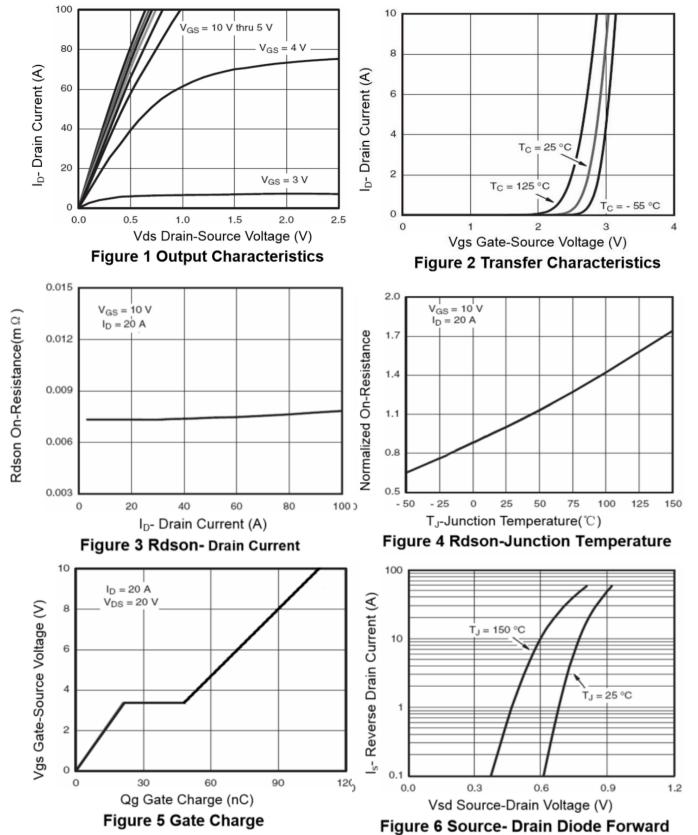
Electrical Characteristics (T_J=25℃, unless otherwise noted)

Symbol	Parameter Conditions		Min.	Тур.	Max.	Unit
BVDSS	Drain-Source Breakdown Voltage	V _{GS} =0V , I _D =-250uA	-40	-44		V
△BVdss/△TJ	BV _{DSS} Temperature Coefficient	Reference to 25°C , I _D =-1mA		-0.023		V/°C
		V _{GS} =-10V , I _D =-12A		7.0	10	
Rds(on)	Static Drain-Source On-Resistance ²	V _{GS} =-4.5V , I _D =-12A 9.0		15	mΩ	
V _{GS(th)}	Gate Threshold Voltage	V _{GS} =V _{DS} , I _D =-250uA	-1.2	-1.8	-2.5	V
Ipss	Drain Source Leakage Current	V _{DS} =-40V , V _{GS} =0V , T _J =25°C			1	uA
IDSS	Drain-Source Leakage Current	V _{DS} =-40V , V _{GS} =0V , T _J =55°C			5	
Igss	Gate-Source Leakage Current	V _{GS} =±20V , V _{DS} =0V			±100	nA
gfs	Forward Transconductance	V _{DS} =-15V , I _D =-12A		20		S
Rg	Gate Resistance	V _{DS} =0V , V _{GS} =0V , f=1MHz		7	14	Ω
Qg	Total Gate Charge (-4.5V)			27.9		
Qgs	Gate-Source Charge	V _{DS} =-20V , V _{GS} =-10V ,		7.7		nC
Q_{gd}	Gate-Drain Charge			7.5		
Td(on)	Turn-On Delay Time			40		
Tr	Rise Time	V_{DD} =-20V , V_{GS} =-10V , R_{G} =3.0 Ω ,		35.2		no
Td(off)	Turn-Off Delay Time	I _D =-12A		100		ns
T _f	Fall Time			9.6		
Ciss	Input Capacitance			6500		
Coss	Output Capacitance	V _{DS} =-20V , V _{GS} =0V , f=1MHz		790		pF
Crss	Reverse Transfer Capacitance			605		
ls	Continuous Source Current ^{1,5}	V _G =V _D =0V , Force Current			-70	Α
VsD	Diode Forward Voltage² V _{GS} =0V , I _S =-1A , T _J =25°C				-1.2	V

Note:

- 1. The data tested by surface mounted on a 1 inch2 FR-4 board with 2OZ copper.
- 2. The data tested by pulsed , pulse width $\leq 300 \text{us}$, duty cycle $\leq 2\%$
- $3\$ The EAS data shows Max. rating . The test condition is VDD=-32V,VGS=-10V,L=0.1mH,IAS=-50A
- 5. The data is theoretically the same as ID and IDM, in real applications, should be limited by total power dissipation.

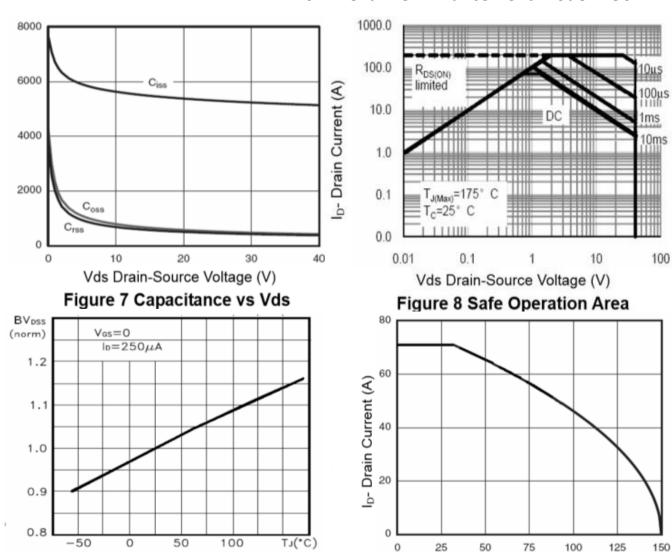






C Capacitance (pF)

-40V P-Channel Enhancement Mode MOSFET



T_J-Junction Temperature(°C)

Figure 9 BV_{DSS} vs Junction Temperature

Figure 10 ID Current Derating vs Junction Temperature

T_J-Junction Temperature(°C)

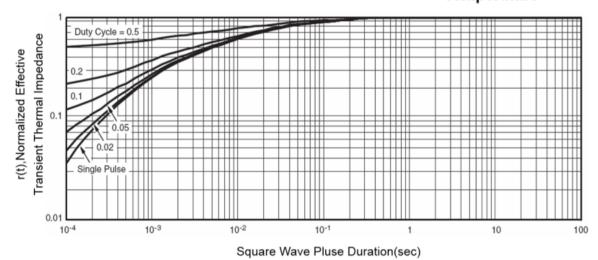
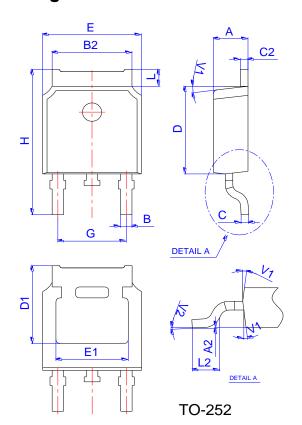


Figure 11 Normalized Maximum Transient Thermal Impedance

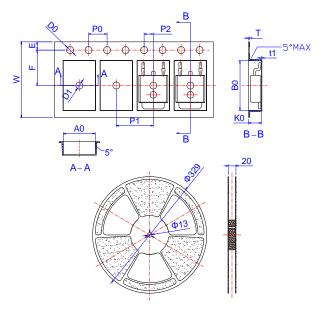


Package Mechanical Data: TO-252-3L



	Dimensions					
Ref.	Millimeters		rs .	Inches		
	Min.	Тур.	Max.	Min.	Тур.	Max.
Α	2.10		2.50	0.083		0.098
A2	0		0.10	0		0.004
В	0.66		0.86	0.026		0.034
B2	5.18		5.48	0.202		0.216
С	0.40		0.60	0.016		0.024
C2	0.44		0.58	0.017		0.023
D	5.90		6.30	0.232		0.248
D1	5.30REF			0.209REF		
E	6.40		6.80	0.252		0.268
E1	4.63			0.182		
G	4.47		4.67	0.176		0.184
Н	9.50		10.70	0.374		0.421
L	1.09		1.21	0.043		0.048
L2	1.35		1.65	0.053		0.065
V1		7°			7°	
V2	0°		6°	0°		6°

Reel Spectification-TO-252



	Dimensions					
Ref.	Millimeters Inche		Inches	3		
	Min.	Тур.	Max.	Min.	Тур.	Max.
W	15.90	16.00	16.10	0.626	0.630	0.634
Е	1.65	1.75	1.85	0.065	0.069	0.073
F	7.40	7.50	7.60	0.291	0.295	0.299
D0	1.40	1.50	1.60	0.055	0.059	0.063
D1	1.40	1.50	1.60	0.055	0.059	0.063
P0	3.90	4.00	4.10	0.154	0.157	0.161
P1	7.90	8.00	8.10	0.311	0.315	0.319
P2	1.90	2.00	2.10	0.075	0.079	0.083
A0	6.85	6.90	7.00	0.270	0.271	0.276
В0	10.45	10.50	10.60	0.411	0.413	0.417
K0	2.68	2.78	2.88	0.105	0.109	0.113
Т	0.24		0.27	0.009		0.011
t1	0.10			0.004		
10P0	39.80	40.00	40.20	1.567	1.575	1.583



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Edition	Date	Change
Rve1.0	2020/10/8	Initial release

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